Dislocation Type Evolution in Compressed Polycrystalline Nickel: Validation of Ashby's Model

<u>Chaoyi Zhu*</u>, Tyler Harrington*, Olivia Dippo*, George T. Gray III`, and Kenneth S. Vecchio*

*Department of NanoEngineering and Materials Science and Engineering Program, UC San Diego, La Jolla CA, 92131 `Los Alamos National Laboratory, Materials Science and Technology Division, Los Alamos, NM 87545





EST. 1943

Dislocation Type: GND and SSD

Geometrically Necessary Dislocation



- 1. Accommodate lattice curvature associated with non-uniform deformation.
- 2. Obstacles to motions of SSD (work hardening).
- 3. Can be quantified in EBSD.

Statistically Stored Dislocation



- 1. Generated due to random trapping process
- 2. Nucleation source for GNDs
- 3. Obstacles to motions of GND (work hardening)
- 4. Can not be quantified in EBSD



GND and SSD Evolution (Ashby)



 λ_G : average slip distance (~grain size) γ : shear strain (Taylor's factor times compressive strain) b: Burgers vector Correction of the materials overlap through GNDs



Ashby's model:

 ρ_{GND} : microstructure (λ_G) and strain dependent (γ)

 ρ_{SSD} : strain dependent (~ γ^2 , measured in strained single crystal fcc crystal at room temperature by Basinski)

Grain size~30 μm , $\rho_{SSD} > \rho_{GND}$ at 0.1 strain



Dislocation Density Tensor

• Fundamental equation: Nye dislocation density tensor α

$$B = -\oint_{C} \beta^{pl} dx = - \oint_{S} \nabla \times \beta^{pl} dS = \oint_{S} \nabla \times \beta^{el} dS = \oint_{S} \alpha dS$$

Stokes' theorem Compatibility Demands
$$\int_{C} \frac{1}{s} \int_{C} \frac{1}{s} \int_{C}$$

Dislocation density tensor describes the dislocation flux through the surface S.

Nye, 1953



Dislocation Density Tensor

• Nye tensor under infinitesimal elastic strain assumption

$$\alpha_{i\gamma} = \epsilon_{\alpha\beta\gamma}\beta^{el}_{i\alpha,\beta} = \epsilon_{\alpha\beta\gamma}\omega_{i\alpha,\beta} + \epsilon_{jlk}\epsilon_{ij,l} \approx \epsilon_{\alpha\beta\gamma}\omega_{i\alpha,\beta} \approx \epsilon_{\alpha\beta\gamma}\Delta\phi_{i\alpha,\beta}$$

$$\boldsymbol{\alpha} \approx \begin{bmatrix} \frac{\partial \omega_{12}}{\partial x_3} - \frac{\partial \omega_{13}}{\partial x_2} & \frac{\partial \omega_{13}}{\partial x_1} & \frac{\partial \omega_{21}}{\partial x_1} \\ \frac{\partial \omega_{32}}{\partial x_2} & \frac{\partial \omega_{23}}{\partial x_1} - \frac{\partial \omega_{21}}{\partial x_3} & \frac{\partial \omega_{21}}{\partial x_2} \\ \frac{\partial \omega_{32}}{\partial x_3} & \frac{\partial \omega_{13}}{\partial x_3} & \frac{\partial \omega_{31}}{\partial x_2} - \frac{\partial \omega_{32}}{\partial x_1} \end{bmatrix}$$

 ω : lattice rotation matrix $\Delta \phi$: disorientation matrix

Latin: crystal coordinates Greek: sample coordinates

Elastically rigid plastic approximation: inhomogeneous plastic distortion of the lattice is fully accommodated by the elastic lattice rotation alone. B.C. Larson *et al.*, 2007



Measuring Lattice Orientation Gradient

- Orientation gradient in the sample surface normal direction is inaccessible in 2D-EBSD
 - $\boldsymbol{\alpha} \approx \begin{bmatrix} \frac{\partial \omega_{12}}{\partial x_3} \frac{\partial \omega_{13}}{\partial x_2} & \frac{\partial \omega_{13}}{\partial x_1} & \frac{\partial \omega_{21}}{\partial x_1} \\ \frac{\partial \omega_{32}}{\partial x_2} & \frac{\partial \omega_{23}}{\partial x_1} \frac{\partial \omega_{21}}{\partial x_3} & \frac{\partial \omega_{21}}{\partial x_2} \\ \frac{\partial \omega_{32}}{\partial x_3} & \frac{\partial \omega_{13}}{\partial x_3} & \frac{\partial \omega_{31}}{\partial x_2} \frac{\partial \omega_{32}}{\partial x_1} \end{bmatrix}$
- Frame of reference: the lattice orientation gradient $\Delta \phi_{i\alpha,\beta}$ needs to be in the sample frame, same as the scan step

$$\Delta \phi_{dis} = \min\{\cos^{-1}\{tr[O_j^{cry}\mathbf{g}_B)(O_i^{cry}\mathbf{g}_A)^{-1}]\}\}$$
$$\Delta \phi_{i\alpha,\beta} \approx \frac{[(O_j^{cry}\mathbf{g}_B)(O_i^{cry}\mathbf{g}_A)^{-1} - I]\mathbf{g}_A}{scan step}$$

Electron Backscatter Diffraction







Dislocation Density Calculation

• Consistency in coordinates system is required, Wheeler *et al*, 2009

$$\alpha_{\alpha\gamma} \approx \mathbf{g}_{\alpha i} (\epsilon_{\alpha\beta\gamma} \Delta \emptyset_{i\alpha,\beta})$$

• Solve for the dislocation density vector ρ :

$$\xi(6 \times N) \cdot \rho(N \times 1) = \Lambda(6 \times 1)$$

$$\begin{pmatrix} b_{1}^{1}l_{1}^{1} - \frac{1}{2}\boldsymbol{b}^{1} \cdot \boldsymbol{l}^{1}, \cdots, b_{1}^{N}l_{1}^{N} - \frac{1}{2}\boldsymbol{b}^{N} \cdot \boldsymbol{l}^{N} \\ b_{1}^{1}l_{2}^{1}, \cdots, b_{1}^{N}l_{2}^{N} \\ b_{1}^{1}l_{3}^{1}, \cdots, b_{1}^{N}l_{3}^{N} \\ b_{2}^{1}l_{1}^{1}, \cdots, b_{2}^{N}l_{1}^{N} \\ b_{2}^{1}l_{2}^{1} - \frac{1}{2}\boldsymbol{b}^{1} \cdot \boldsymbol{l}^{1}, \cdots, b_{2}^{N}l_{2}^{N} - \frac{1}{2}\boldsymbol{b}^{N} \cdot \boldsymbol{l}^{N} \\ b_{2}^{1}l_{3}^{1}, \cdots, b_{2}^{N}l_{3}^{N} \end{pmatrix} \begin{pmatrix} \rho_{1} \\ \vdots \\ \rho_{N} \end{pmatrix} = \begin{pmatrix} \frac{1}{2}\boldsymbol{T}(\boldsymbol{\alpha}) - \alpha_{11} \\ -\alpha_{12} \\ -\alpha_{13} \\ -\alpha_{21} \\ \frac{1}{2}\boldsymbol{T}(\boldsymbol{\alpha}) - \alpha_{22} \\ -\alpha_{23} \end{pmatrix}$$

 $\alpha_{\alpha\gamma} = \sum_{\alpha} \rho_{GND}^n b_{\alpha}^n \hat{l}_{\gamma}^n$

Britton and Wilkinson, 2012

• N>6: L1 dislocation energy minimization scheme ($E_{edge} = E_{screw}/(1-v)$, v is the Poisson's ratio): $minimum \left\{ E_{GND,total}^{L^{1e}} = E_N \cdot \rho \mid \xi' \subset \xi, \Lambda = \xi' \cdot \rho \right\}$



Measurement Resolution (Lower Limit)

- Angular resolution of EBSD is between 0.2°~1°
- Resolution of GND measurement is limited by angular resolution and step size
- Noise floor:

$$\rho_{GND}^{res} = \frac{\text{Angular Resolution (rad)}}{\text{Step size (m)} \times \text{Burgers vector(m)}}$$

Humphreys et al, 2001 Wilkinson and Randman, 2010



Measurement Resolution (Upper Limit)



Pattern degradation due to severe plastic deformation.



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Wright et al., 2011

Appropriate Step Size (Burgers Circuit Size)

- L>> average spacing between dislocations $(1/\sqrt{\rho_{GND}})$
- L<< length scale over which there is significant variation in the plastic deformation field $(1/b \cdot \rho_{GND})$





Material Fabrication and Characterization



Nickel powder SPS 1200°C under a 50 MPa uniaxial load for a 5-minute hold and then annealed (~99% density)

Zhu et al, Acta Materialia, 2018



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Materials and Sample Preparation



3 mm by 3 mm cylinder



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EBSD Scans

Imposed plastic strain varying from 0.05 to 0.46



200 µm _____

Zhu et al, Acta Materialia, 2018



Deformation Heterogeneity



[111]

≤13.5

Deformation is highly heterogenous

^{≥15.3} GND hot spots

- Geometric constraint (b)(d)(f)
- Orientation constraint (h)

10 µm

Zhu et al, Acta Materialia, 2018



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GND Density Data Distribution



Zhu *et al*, Acta Materialia, 2018 Jiang et al, Acta Materialia, 2013



March 10-14, 2019 · San Antonio, Texas, USA #TMSAnnualMeeting · www.tms.org/TMS2019 2. more heterogenous dislocation distribution (1 variance).

Ashby and Measured GND Comparison



Zhu et al, Acta Materialia, 2018



Taylor's Hardening Model



$$\sigma_{flow} = \overline{m}\tau = \overline{m}cGb\sqrt{\rho_T}$$
$$\rho_T = \frac{\sigma_{flow}^2}{(\overline{m}cGb)^2}$$
$$\rho_{SSD} = \rho_T - \rho_{GND}$$

Frictional stress in FCC is negligibly small ($\tau_0 = 0$); \overline{m} : Taylor's factor; c: 0.3; G: shear modulus; b: Burgers vector

Taylor, 1938 Kubin and Mortensen, 2003 Jiang *et al*, 2013

Zhu et al, Acta Materialia, 2018



Dislocation Type Evolution @ R.T.





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Future Directions

- Lower strain<0.05 (HR-EBSD)
- Grain size effect
- Temperature effect
- Strain rate effect
- Change materials



Thank you







Effect of varying step size



Appropriateness of Step Size

